

**Search Notes**

Application/Control No.

10/028,060

Examiner

Sy D. Luu

Applicant(s)/Patent under  
Reexamination

NEWELL ET AL.

Art Unit

2174

**SEARCHED**

Class	Subclass	Date	Examiner
715	760,853, 854	8/7/2006	SL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
US-PGPUB		11/9/2006	SL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT US-PGPUB	8/7/2006	SL
Text Searches:  715/760,733,741,743-747,810,851- 855,705,712-713,961,962,700  715/501.1,513  705/1,8	8/7/2006	SL
PLUS	7/27/2006	SL
STIC (EIC)	10/24/2006	SL
UPDATED	11/9/2006	SL